

**ABSTRACT**

This user's guide describes the evaluation module (EVM) for the variants of TPS25946 eFuse family. The TPS25946 device is a 2.7 V to 23 V, 5.5-A eFuse with integrated 28.3-m Ω FET. The TPS25946 family of eFuses have reverse current protection when disabled, bi-directional current flowing capability when enabled, adjustable overcurrent, inrush current, short-circuit, overtemperature protections, adjustable overcurrent transient blanking timer, adjustable undervoltage and overvoltage protections, and user defined output slew rate control.

Table of Contents

1 Introduction	3
1.1 EVM Features.....	3
1.2 EVM Applications.....	3
2 Description	3
3 Schematic	4
4 General Configurations	5
4.1 Physical Access.....	5
4.2 Test Equipment and Set up.....	6
5 Test Setup and Procedures	6
5.1 Hot Plug Test.....	7
5.2 Startup With a Combination of Capacitive and Resistive Loads.....	8
5.3 Power-Up into Short Test.....	9
5.4 Overvoltage Lockout Test.....	10
5.5 Transient Overload Performance.....	11
5.6 Overcurrent Test.....	12
5.7 Output Hot Short Test.....	15
5.8 USB On-The-Go (OTG) Performance.....	16
6 EVAL Board Assembly Drawings and Layout Guidelines	17
6.1 PCB Drawings.....	17
7 Bill Of Materials (BOM)	19
8 Revision History	22

List of Figures

Figure 3-1. TPS25946EVM eFuse Evaluation Board Schematic.....	4
Figure 5-1. TPS25946EVM Setup with Test Equipment.....	6
Figure 5-2. TPS259460x Hot Plug Profile (VIN = 12 V, Cout = 220 μ F, CdVdt = 3300 pF, No Load).....	7
Figure 5-3. TPS259461x Hot Plug Profile (VIN = 12 V, Cout = 220 μ F, CdVdt = 10 nF, No Load).....	8
Figure 5-4. TPS259460x Startup Profile With a Combination of Capacitive and Resistive Load (VIN = 12 V, Cout = 470 μ F, Rout = 5 Ω , CdVdt = 3300 pF).....	9
Figure 5-5. Power-Up into Output Short Response of TPS259460x eFuse (VIN Stepped Up From 0 V to 12 V, RILM = 549 Ω , CITimer = 2.2 nF, OUT Shorted to PGND).....	10
Figure 5-6. Power-Up into Output Short Response of TPS259461x eFuse (VIN = 12 V, RILM = 549 Ω , CITimer = 2.2 nF, OUT Shorted to PGND, VEN/UVLO Stepped Up From 0 V to 1.3 V).....	10
Figure 5-7. Overvoltage Lockout Response of TPS25946 eFuse (VIN Ramped Up From 12 V to 16 V, Cout = 220 μ F, Rout = 20 Ω , VIN Overvoltage Lockout Threshold Set to 13.2 V).....	11
Figure 5-8. Transient Overload Performance of TPS25946 eFuse (VIN = 12 V, CITimer = 2.2 nF, Cout = 470 μ F, RILM = 549 Ω , IOU Ramped From 4 A to 8 A Then 4 A Within 1 ms).....	12
Figure 5-9. Current Limit Response of TPS259460x (VIN = 12 V, CITimer = 2.2 nF, Cout = 220 μ F, RILM = 549 Ω , IOU Stepped From 3 A to 9 A for 4.7 ms).....	13
Figure 5-10. Current Limit Response of TPS259460x (VIN = 12 V, CITimer = 2.2 nF, Cout = 220 μ F, RILM = 549 Ω , IOU Stepped From 3 A to 9 A for 8 ms).....	13

Figure 5-11. Current Limit Response of TPS259461x (VIN = 12 V, CITimer = 2.2 nF, Cout = 220 μ F, RILM = 549 Ω , IOUT Stepped From 0 A to 10 A for 8 ms).....	14
Figure 5-12. Output Hot Short Response of TPS25946 Device (Vin = 12 V, Cout = 10 μ F, ILIM = 549 Ω).....	15
Figure 5-13. Output Hot Short Response (Zoomed) of TPS25946 Device (Vin = 12 V, Cout = 10 μ F, ILIM = 549 Ω).....	15
Figure 5-14. Schematic to Evaluate USB On-The-Go (OTG) Port Protection Performance of TPS25946x eFuse.....	16
Figure 5-15. Power-Up of TPS25946 eFuse During USB On-The-Go (OTG) Mode (VSYSTEM = 5 V, IBUS = 0.2 A, CdVdt = OPEN).....	17
Figure 6-1. TPS25946EVM Board (a) Top Assembly (b) Bottom Assembly.....	17
Figure 6-2. TPS25946EVM Board (a) Top Layer (b) Bottom Layer.....	18

List of Tables

Table 2-1. TPS25946EVM eFuse Evaluation Board Options and Setting.....	3
Table 4-1. Input and Output Connector Functionality.....	5
Table 4-2. Test Points Description.....	5
Table 4-3. Jumper Descriptions and Default Positions.....	5
Table 4-4. LED Descriptions.....	6
Table 5-1. Default Jumper Setting for TPS25946EVM eFuse Evaluation Board.....	6
Table 7-1. TPS25946EVM BOM.....	19

Trademarks

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1 Introduction

The *TPS25946EVM eFuse Evaluation Board* allows reference circuit evaluation of Texas Instruments (TI) TPS25946 eFuse. The TPS25946 device is a 2.7 V to 23 V, 5.5-A eFuse with integrated 28.3-mΩ FET. The TPS25946 family of eFuses have reverse current protection when disabled, bi-directional current flowing capability when enabled, adjustable overcurrent, inrush current, short-circuit, overtemperature protections, adjustable overcurrent transient blanking timer, adjustable undervoltage and overvoltage protections, and user defined output slew rate control.

1.1 EVM Features

General TPS25946EVM eFuse evaluation board features include:

- 2.7-V to 23-V (typ.) operation
- 0.5-A to 6-A programmable current limit using onboard jumpers
- Adjustable output voltage slew rate control
- Adjustable transient current blanking timer
- Adjustable current limit
- TVS diode for both input and output transient protection
- On-board Schottky diode at output prevents negative spike during overcurrent faults
- LED status for Power Good indication

1.2 EVM Applications

This EVM can be used on the following applications:

- Smart phones
- Tablets
- USB On-The-Go (OTG)
- POS terminals
- Digital camera

2 Description

The TPS25946EVM eFuse Evaluation Board enables the evaluation of TPS259460x and TPS259461x eFuses from TPS25946 family. This EVM comes with adjustable ITimer, dV/dt, ILM, and PGTH settings. The input power is applied at connector J1, while J2 provides the output connection for the EVM; refer to the schematic in [Figure 3-1](#), and EVM test setup in [Figure 5-1](#). TVS diodes U2 and U3 provide input protection from transient overvoltages, while Schottky diode D2 provides output protection for the TPS25946. TVS diode U3 is useful to protect the device during transient caused by short circuit at the connector J1 when power is flowing from OUT (Connector J2) to IN (Connector J1).

S1 allows U1 to be RESET or disabled. A Power Good (PG) indicator is provided by a LED D3. Scaled device current can be monitored at TP8 with a factor of 0.13 V/A.

Table 2-1. TPS25946EVM eFuse Evaluation Board Options and Setting

EVM Function	Vin UVLO Threshold	Vin OVLO Threshold	ITimer	Output Slew Rate (dv/dt)	Power Good Threshold (PGTH)	Current Limit	
						Low Setting	High Setting
Performance evaluation of TPS25946, 2.7 V to 23 V, 5.5-A eFuse	10.83 V	16.38 V	Selectable - 183 μs, 1.83 ms, and 18.3 ms	Selectable - 0.6 mV/μs, 0.2 mV/μs, and 0.09 mV/μs	Selectable - With respect to Input (VIN) and Output (VOUT)	0.5 A	6 A

3 Schematic

Figure 3-1 illustrates the EVM schematic.

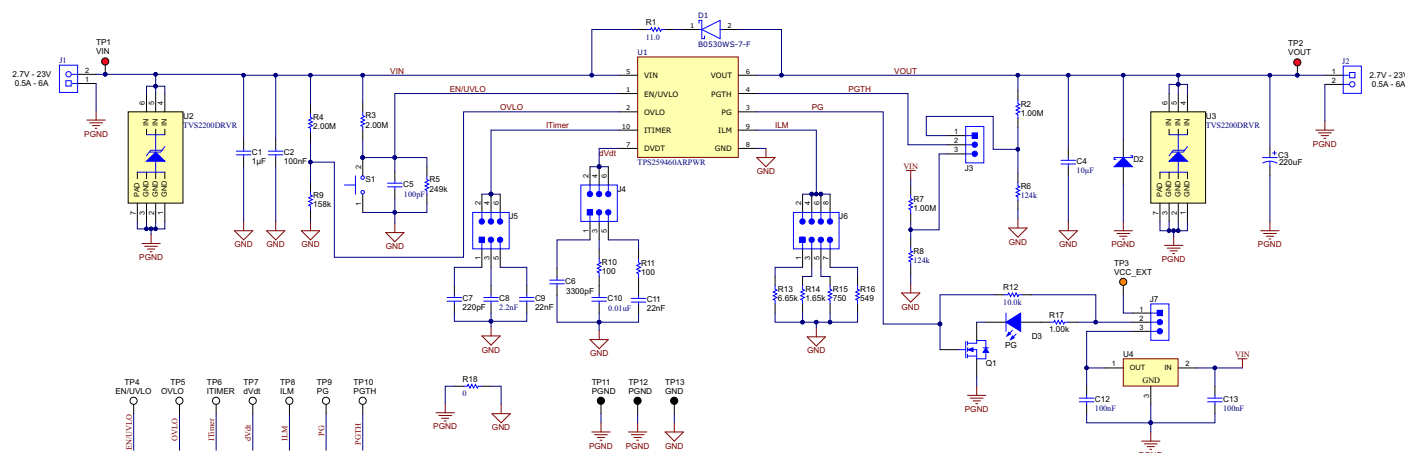


Figure 3-1. TPS25946EVM eFuse Evaluation Board Schematic

Note

In order to evaluate the performance of TPS259461x variants, the jumper J3 needs to be at 2-3 position and the values of resistors R7 and R8 must be selected in such a way that voltage across the resistance, R8, is 3.3 V for a given input voltage of VIN. During the performance evaluation of TPS259461x variants, AUXOFF and FLT signals can be probed at the test points TP9 and TP10 respectively.

4 General Configurations

4.1 Physical Access

Table 4-1 lists the TPS25946EVM eFuse Evaluation Board input and output connectors functionalities. Table 4-2 and Table 4-3 describe the availability of test points and the functionalities of the jumpers. Table 4-4 presents the function of the signal LED.

Table 4-1. Input and Output Connector Functionality

Connector	Label	Description
J1	VIN (+), PGND (-)	Input Power to the eFuse
J2	VOUT (+), PGND (-)	Output Power from the eFuse

Table 4-2. Test Points Description

Test Points	Label	Description
TP1	VIN	Input voltage
TP2	VOUT	Output voltage
TP3	VCC_EXT	External VCC voltage for Power Good indicator
TP4	EN/UVLO	EN/UVLO signal
TP5	OVLO	OVLO signal
TP6	ITimer	ITimer signal
TP7	dVdt	Output voltage ramp control
TP8	ILM	Current limit and monitor signal
TP9	PG	Power Good signal
TP10	PGTH	Power Good threshold signal
TP11 and TP12	PGND	Power GND signal
TP13	GND	IC GND signal

Table 4-3. Jumper Descriptions and Default Positions

Jumper	Label	Description	Default Jumper Position
J3 ⁽¹⁾	PGTH Selection for TPS259460x variants	1-2 PGTH is respect to VOUT	1-2
		2-3 PGTH is respect to VIN	
J4	dVdt	1-2 Position sets Output Slew Rate to 0.6 mV/μs	3-4
		3-4 Position sets Output Slew Rate to 0.2 mV/μs	
		5-6 Position sets Output Slew Rate to 0.09 mV/μs	
J5	ITimer	1-2 Position sets the transient current blanking period to 183 μs	3-4
		3-4 Position sets the transient current blanking period to 1.83 ms	
		5-6 Position sets the transient current blanking period to 18.3 ms	
J6	ILM	1-2 Position sets the current limit to 0.5 A	7-8
		3-4 Position sets the current limit to 2 A	
		5-6 Position sets the current limit to 4.5 A	
		7-8 Position sets the current limit to 6 A	
J7	VCC Connection	1-2 Position connects external voltage, VCC_EXT as reference for PG	2-3
		2-3 Position connects on board generated voltage, VCC as reference for PG	

(1) In order to evaluate the performance of TPS259461x variants, the jumper J3 needs to be at 2-3 position.

Table 4-4. LED Descriptions

LED	Description
D3	When ON, indicates that PG is asserted

4.2 Test Equipment and Set up

4.2.1 POWER SUPPLIES

One adjustable power supply 0-V to 30-V output and 0-A to 10-A output current limit.

4.2.2 METERS

Minimum a Digital Multi Meter (DMM) needed.

4.2.3 OSCILLOSCOPE

A DPO2024 or equivalent, three 10x voltage probes, and a DC current probe.

4.2.4 LOADS

One resistive load or equivalent which can tolerate up to 10-A DC load at 24 V and capable of the output short.

5 Test Setup and Procedures

In this user's guide, the test procedure is described for TPS259460A and TPS259460L devices. Make sure the evaluation board has default jumper settings as shown in [Table 5-1](#).

Table 5-1. Default Jumper Setting for TPS25946EVM eFuse Evaluation Board

J3	J4	J5	J6	J7
1-2	3-4	3-4	7-8	2-3

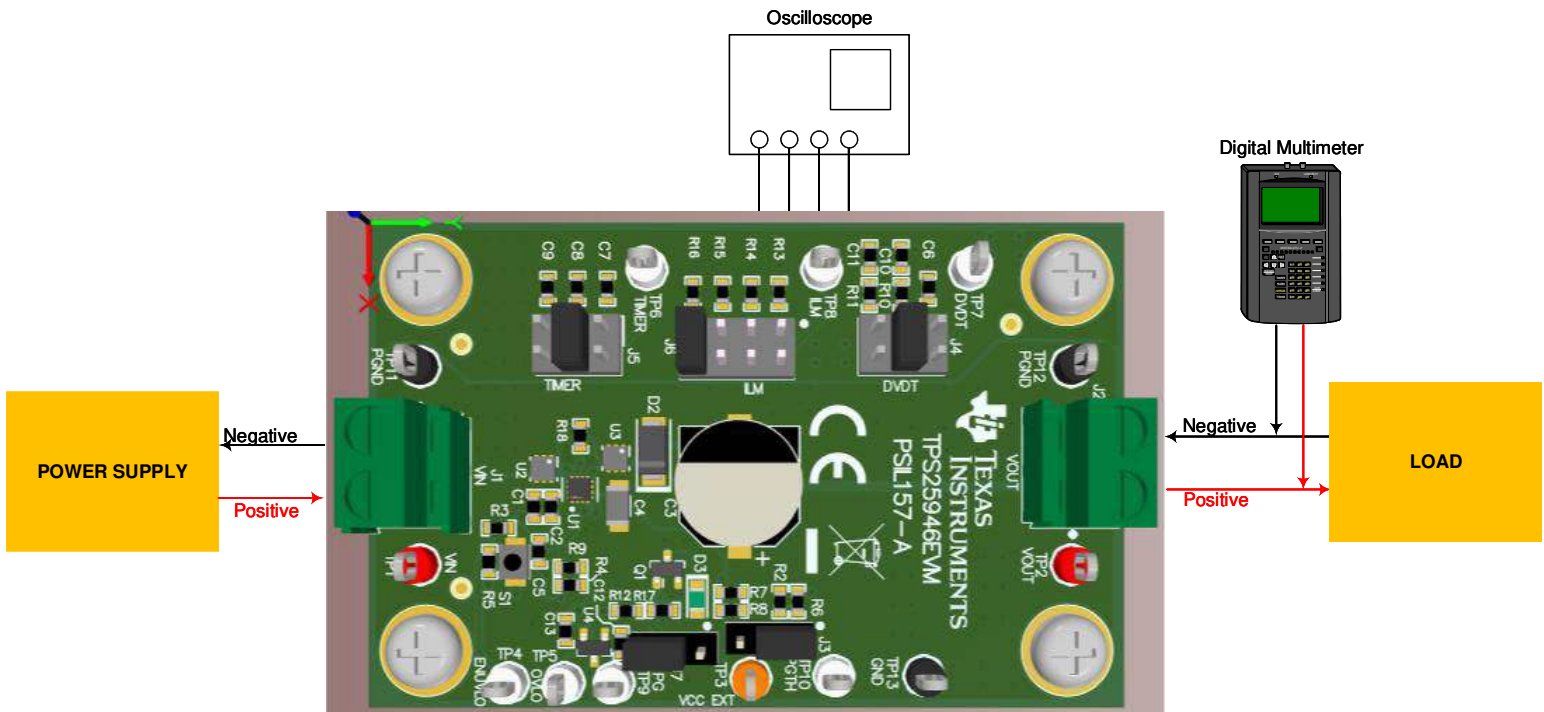


Figure 5-1. TPS25946EVM Setup with Test Equipment

Follow these instructions before starting any test and repeat again before moving to next test:

- Set the power supply output (VIN) to zero volts.
- Turn ON the power supply and set the power supply output (VIN) to 12 V, current limit of 10 A.
- Turn OFF the power supply.
- Set the jumper setting on EVM to default positions as shown in [Table 5-1](#).

5.1 Hot Plug Test

Use the following instructions to measure the inrush current during hot plug event:

1. Set Jumper J4 position to desired slew rate as mentioned in [Table 4-3](#).
2. Set the input supply voltage VIN to 12 V and current limit of 10 A. Enable the power supply.
3. Hot plug the supply between VIN and PGND points of connector J1.
4. Observe the waveforms at VOUT (TP2) and input current with an oscilloscope to measure the slew rate and rise time of the eFuse with a given input voltage of 12 V.

Figure 5-2 and Figure 5-3 show the examples of inrush current captured on the TPS25946EVM eFuse Evaluation Board during hot plug event using TPS259460x and TPS259461x variants respectively.

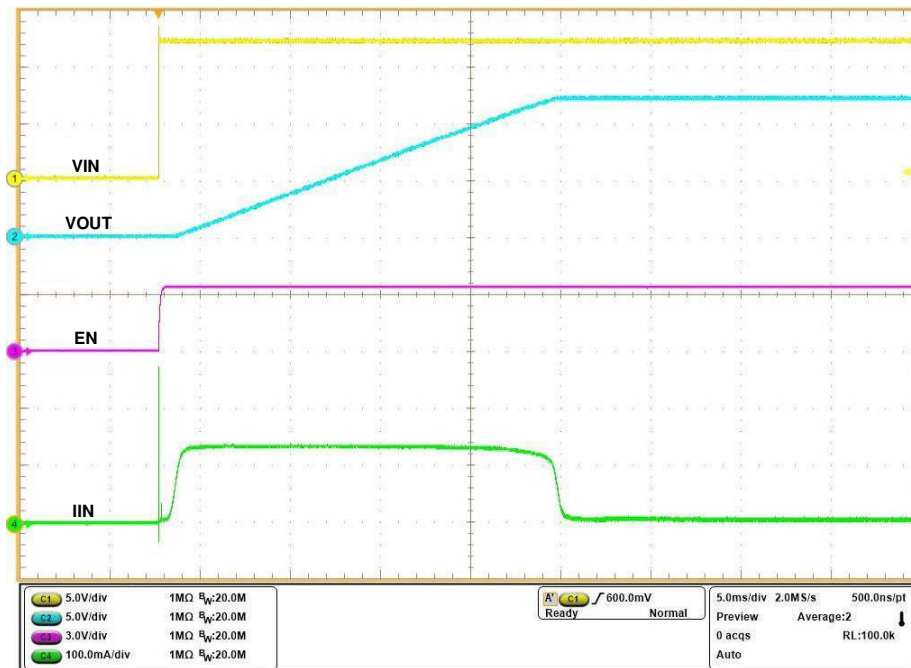


Figure 5-2. TPS259460x Hot Plug Profile (VIN = 12 V, Cout = 220 μ F, CdVdt = 3300 pF, No Load)

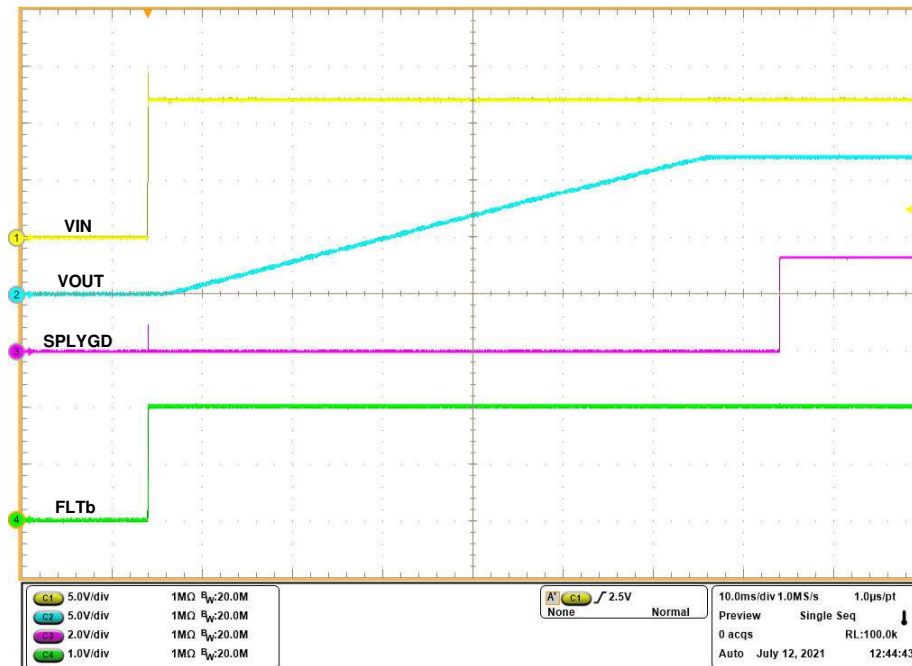


Figure 5-3. TPS259461x Hot Plug Profile (VIN = 12 V, Cout = 220 μ F, CdVdt = 10 nF, No Load)

5.2 Startup With a Combination of Capacitive and Resistive Loads

Use the following instructions to power-up the TPS259460x and TPS259461x eFuses with capacitive and resistive loads:

1. Set Jumper J4 position to desired slew rate as mentioned in [Table 4-3](#).
2. Set the input supply voltage VIN to 12 V and current limit of 10 A.
3. Connect a load of 5 Ω between VOUT and PGND points of connector J2.
4. Connect the input supply between VIN and PGND points of connector J1. Enable the power supply.
5. Observe the waveform at VOUT (TP2) and input current with an oscilloscope to measure the slew rate and rise time of the eFuse with a given input voltage of 12 V.

[Figure 5-4](#) shows the startup profile of TPS25946 eFuse with a combination of capacitive and resistive loads.

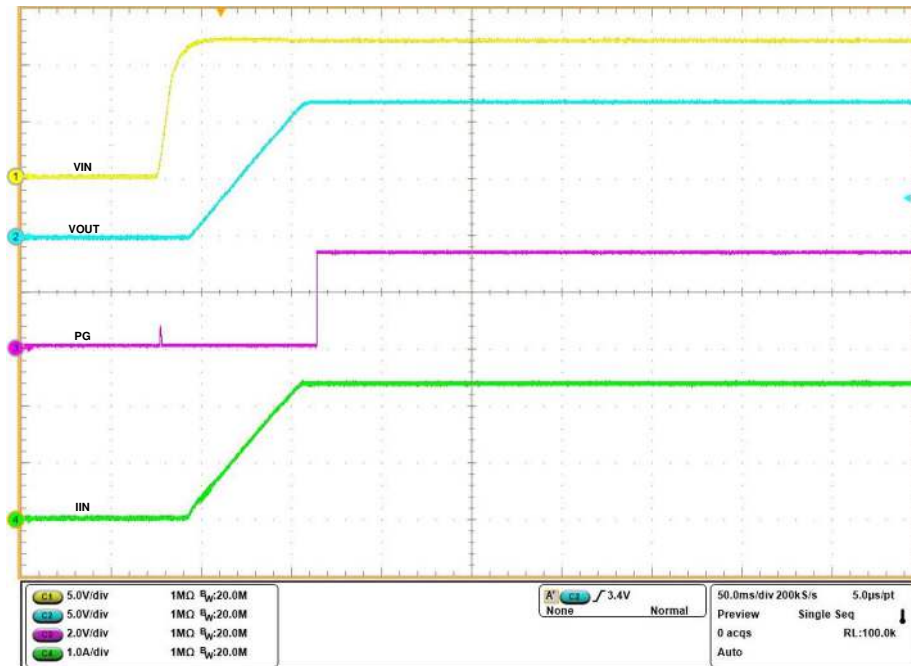


Figure 5-4. TPS259460x Startup Profile With a Combination of Capacitive and Resistive Load ($V_{IN} = 12\text{ V}$, $C_{out} = 470\ \mu\text{F}$, $R_{out} = 5\ \Omega$, $C_dV_{dt} = 3300\ \text{pF}$)

5.3 Power-Up into Short Test

Use the following instructions to perform the power-up into short test:

1. Set the input supply voltage V_{IN} to 12 V and current limit of 10 A. Keep the power supply OFF.
2. Short the output of the device. For example, V_{OUT} to PGND with a shorter cable.
3. Keep the TPS25946 eFuse disabled by pushing the switch S1.
4. Turn ON the power supply.
5. Enable the TPS25946 eFuse by releasing the switch S1.

Figure 5-5 and Figure 5-6 show the test waveforms of power-up into output short on the TPS25946EVM eFuse Evaluation Board for TPS259460x and TPS259461x variants respectively.

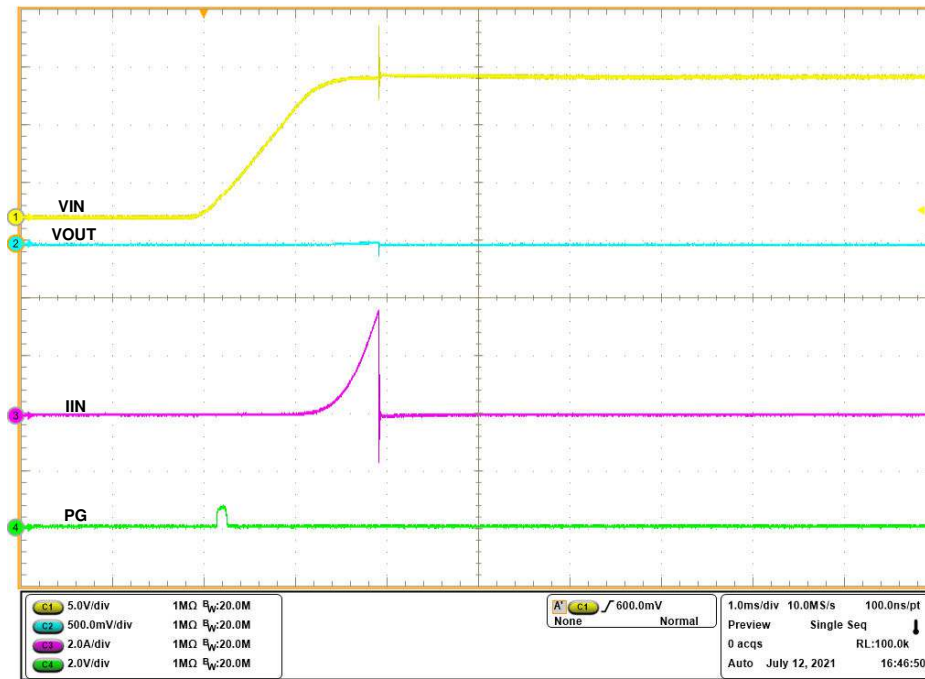


Figure 5-5. Power-Up into Output Short Response of TPS259460x eFuse (VIN Stepped Up From 0 V to 12 V, RILM = 549 Ω , CITimer = 2.2 nF, OUT Shorted to PGND)

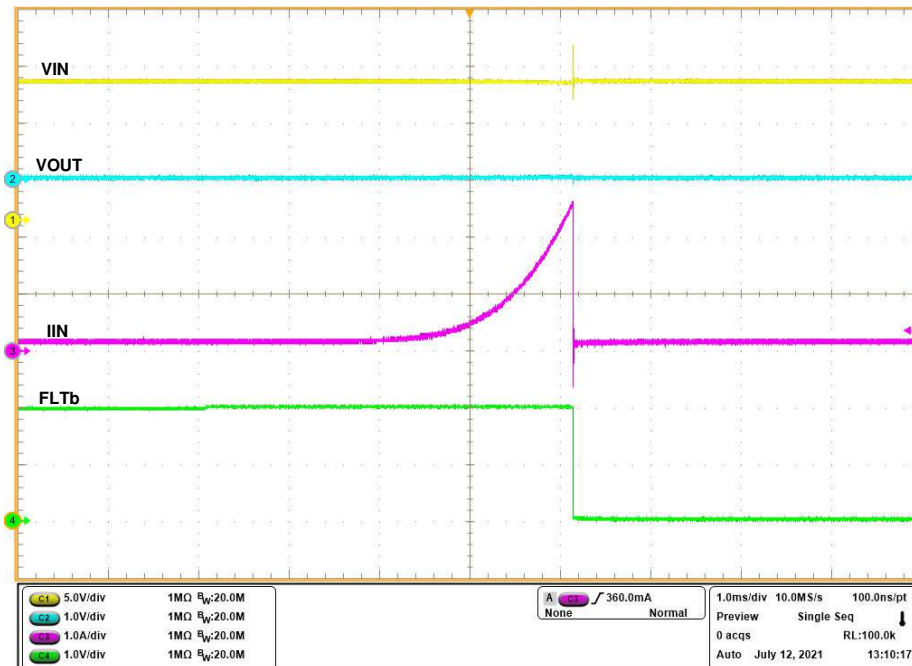


Figure 5-6. Power-Up into Output Short Response of TPS259461x eFuse (VIN = 12 V, RILM = 549 Ω , CITimer = 2.2 nF, OUT Shorted to PGND, VEN/UVLO Stepped Up From 0 V to 1.3 V)

5.4 Overvoltage Lockout Test

Use the following instructions to perform the overvoltage protection test:

1. Set the input supply voltage VIN to 12 V and current limit of 10 A. Apply the supply between VIN and PGND at connector J1 and enable the power supply.
2. Apply a load of 20 Ω between VOUT and PGND at connector J2.
3. Increase the input supply VIN from 12 V to 16 V, and observe the waveforms using an oscilloscope.

Figure 5-7 shows overvoltage lockout response of TPS25946 eFuse on TPS25946EVM eFuse Evaluation Board.

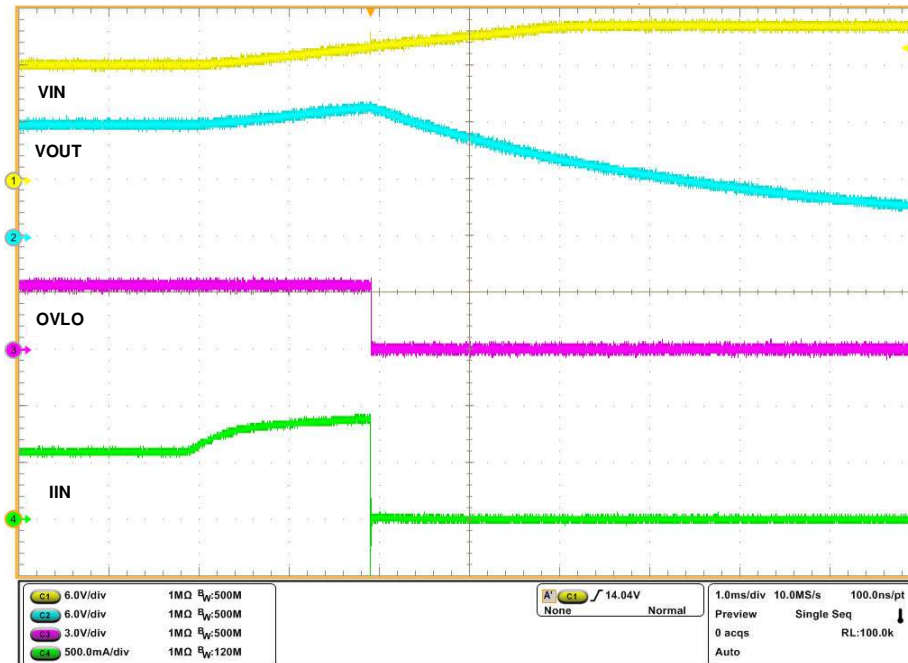


Figure 5-7. Overvoltage Lockout Response of TPS25946 eFuse (VIN Ramped Up From 12 V to 16 V, Cout = 220 μ F, Rout = 20 Ω , VIN Overvoltage Lockout Threshold Set to 13.2 V)

5.5 Transient Overload Performance

Use the following instructions to observe the transient overload performance:

1. Place jumper J5 to an appropriate position to obtain required blanking period as per [Table 4-3](#).
2. Place jumper J6 in a suitable position to set required current limit as per [Table 4-3](#).
3. Set the input supply voltage VIN to 12 V and current limit of 10 A and enable the power supply.
4. Now apply an overload greater than the set current limit (using the jumper J6) between VOUT and PGND for a time duration less than the blanking period decided by using jumper J5.
5. Observe the waveforms using an oscilloscope.

Figure 5-8 shows transient overload performance of TPS25946 eFuse on TPS25946EVM eFuse Evaluation Board.

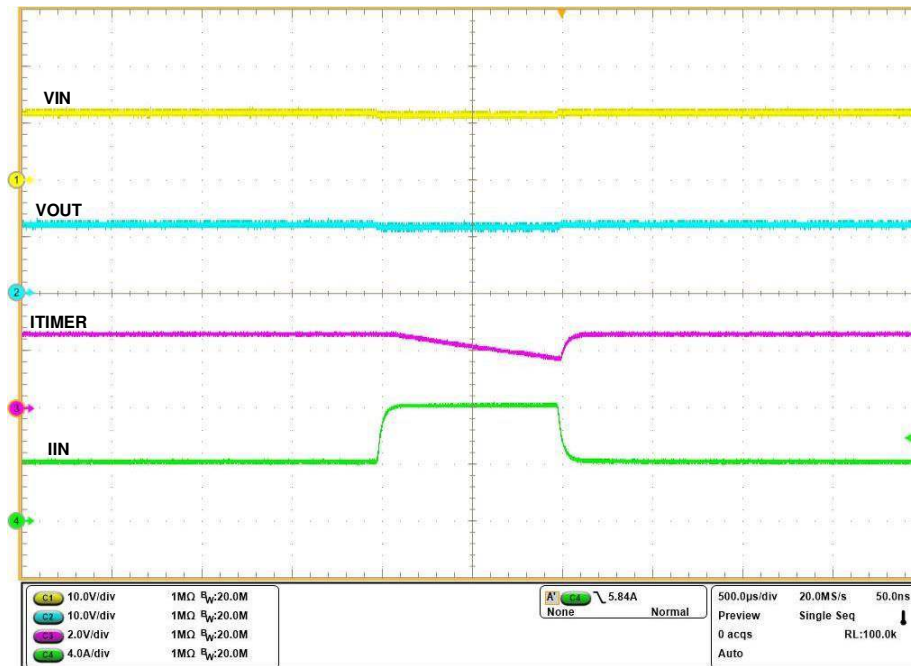


Figure 5-8. Transient Overload Performance of TPS25946 eFuse (VIN = 12 V, CTimer = 2.2 nF, Cout = 470 μF, RILM = 549 Ω, IOUT Ramped From 4 A to 8 A Then 4 A Within 1 ms)

5.6 Overcurrent Test

Use the following instructions to perform the overcurrent test on TPS25946 eFuse:

1. Place jumper J5 to an appropriate position to obtain required blanking period as per [Table 4-3](#).
2. Place jumper J6 in a suitable position to set required current limit as per [Table 4-3](#).
3. Set the input supply voltage VIN to 12 V and current limit of 10 A and enable the power supply.
4. Now apply an overload greater than the set current limit (using jumper J6) between VOUT and PGND (use a resistive load to apply overcurrent).
5. The device responds to output overcurrent condition by actively limiting the current after a user adjustable transient fault blanking interval, set by using jumper J5. During active current limit, the output voltage will drop resulting in increased device power dissipation. If the device internal temperature exceeds the thermal shutdown threshold, the device will turn off.

Figure 5-9, Figure 5-10, and Figure 5-11 show the current limit behaviors of TPS25946 eFuse at different overcurrent fault durations and with different variants.

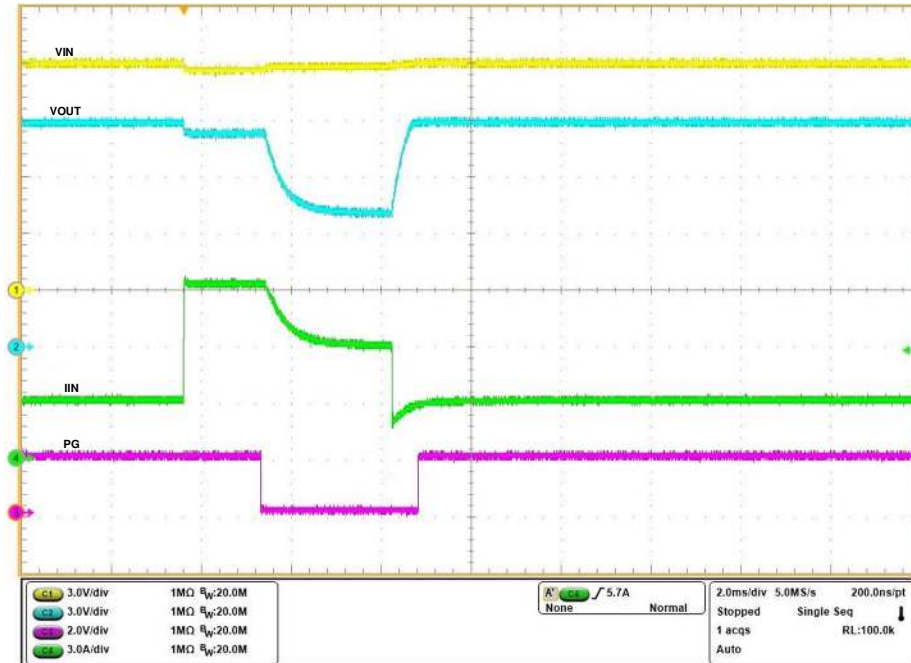


Figure 5-9. Current Limit Response of TPS259460x (VIN = 12 V, CITimer = 2.2 nF, Cout = 220 μ F, RILM = 549 Ω , IOU_T Stepped From 3 A to 9 A for 4.7 ms)

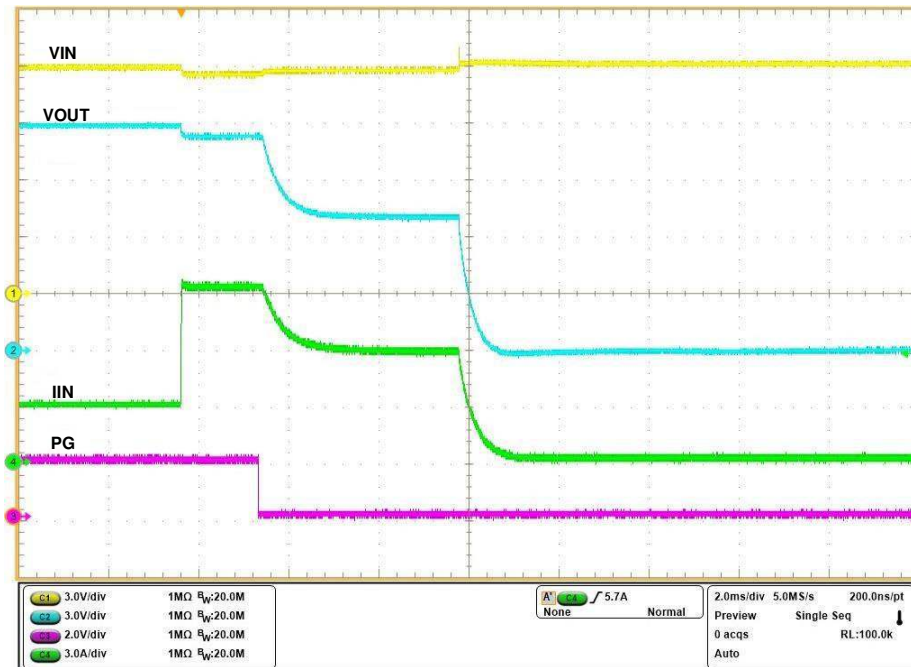


Figure 5-10. Current Limit Response of TPS259460x (VIN = 12 V, CITimer = 2.2 nF, Cout = 220 μ F, RILM = 549 Ω , IOU_T Stepped From 3 A to 9 A for 8 ms)

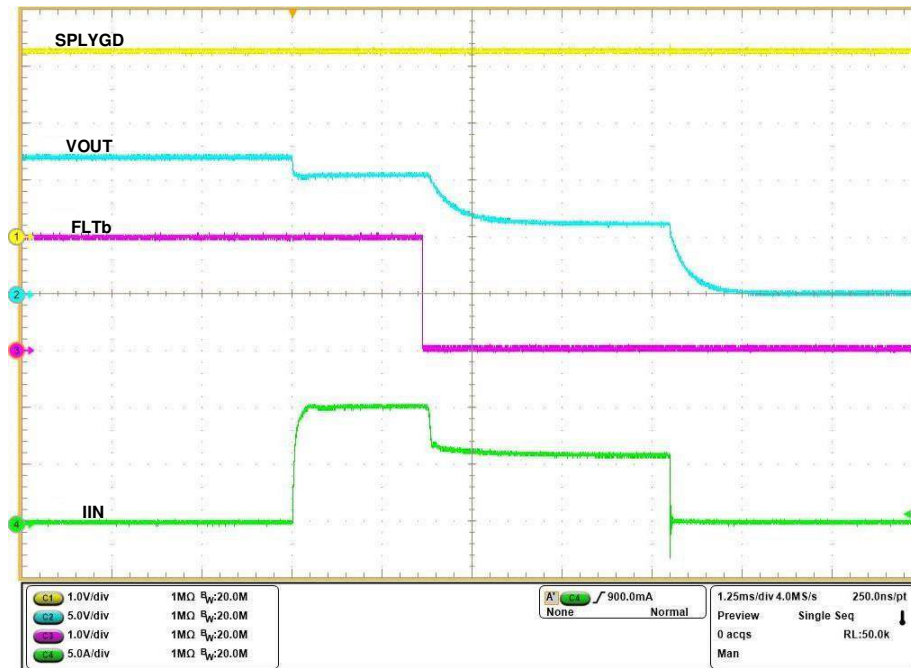


Figure 5-11. Current Limit Response of TPS259461x (VIN = 12 V, CITimer = 2.2 nF, Cout = 220 μF, RILM = 549 Ω, IOU Stepped From 0 A to 10 A for 8 ms)

5.7 Output Hot Short Test

Use the following instructions to perform the output hot short test:

1. Set the input supply voltage V_{IN} to 12 V and current limit of 10 A. Turn ON the power supply.
2. Short the output of the device for example, V_{OUT} to PGND with a shorter cable.
3. Observe the waveforms using an oscilloscope.

Figure 5-12 and Figure 5-13 show the test waveforms of output hot short on the TPS25946EVM eFuse Evaluation Board.

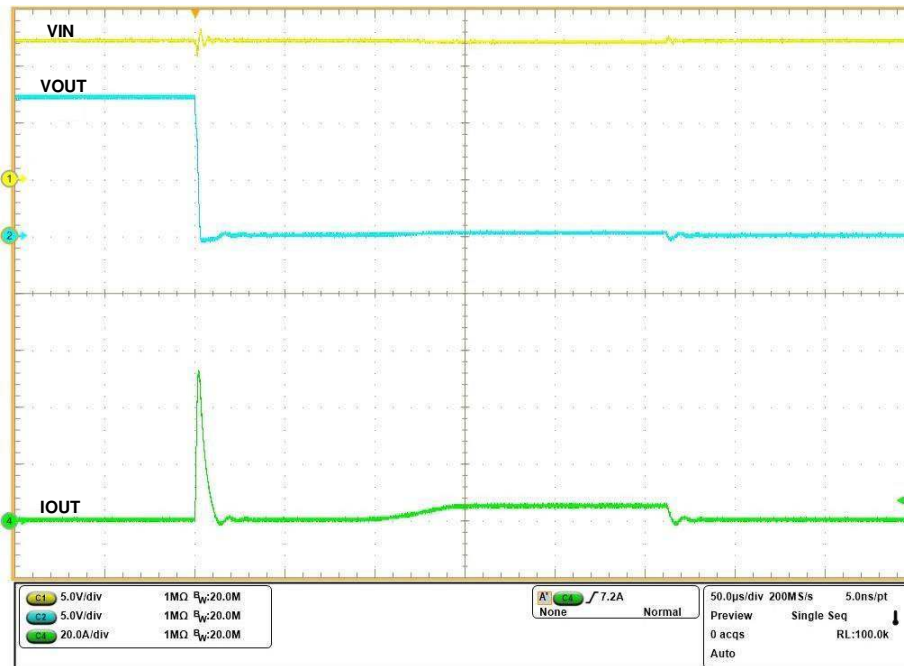


Figure 5-12. Output Hot Short Response of TPS25946 Device ($V_{in} = 12\text{ V}$, $C_{out} = 10\text{ }\mu\text{F}$, $ILIM = 549\text{ }\Omega$)

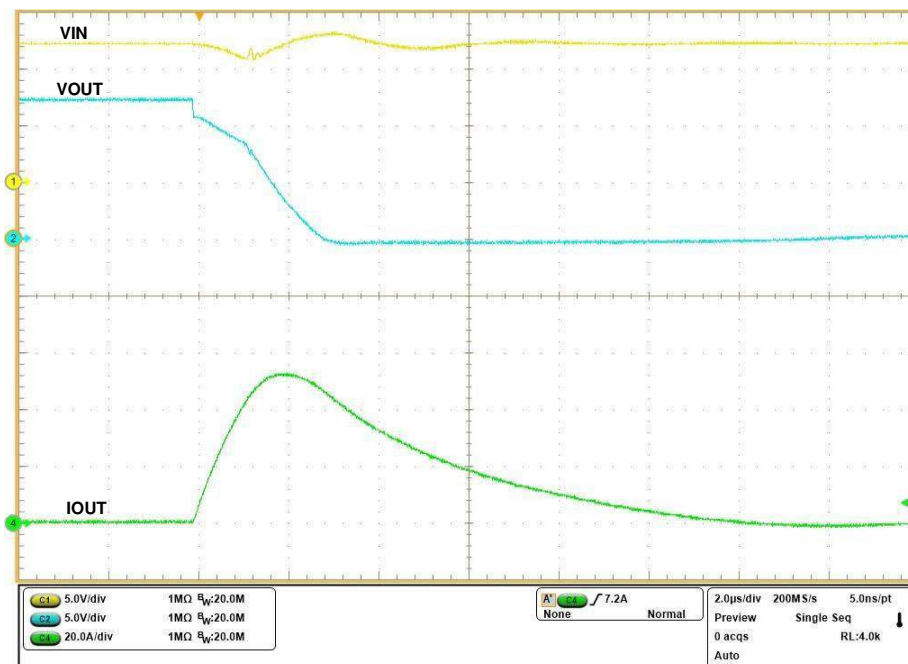


Figure 5-13. Output Hot Short Response (Zoomed) of TPS25946 Device ($V_{in} = 12\text{ V}$, $C_{out} = 10\text{ }\mu\text{F}$, $ILIM = 549\text{ }\Omega$)

Note that it is very difficult to obtain repeatable and similar short-circuit testing results. The following contributes to the variation in results:

- Source bypassing
- Input leads
- Board layout
- Component selection
- Output shorting method
- Relative location of the short
- Instrumentation

The actual short exhibits a certain degree of randomness because it microscopically bounces and arcs. Ensure that configuration and methods are used to obtain realistic results. Hence, do not expect to see waveforms exactly like the waveforms in this user's guide because every setup is different.

5.8 USB On-The-Go (OTG) Performance

Use the following instructions to observe USB On-The-Go (OTG) performance:

1. Set the input supply voltage to 5 V and current limit of 10 A. Apply the supply between VOUT and PGND at connector J2.
2. Connect a load of 200 mA between VIN and PGND at connector J1.
3. Turn on the input power supply at the connector J2.
4. Enable the eFuse by applying 1.5 V externally between TP4 and GND. This external power supply is not required if the EN/UVLO set point is above the voltage between TP1 and PGND before the device getting enabled, which is the difference between the input supply at J2 and the voltage drops across R1 and D1.
5. Note that if the Power Good (PG) signal is required to observe during this OTG mode of operation with 5-V input, the resistor R8 needs to be changed to 360 k Ω .

Figure 5-14 shows the schematic to evaluate USB On-The-Go (OTG) port protection performance of TPS25946x eFuse.

Figure 5-15 shows the power-up of TPS25946x eFuse during USB On-The-Go (OTG) mode.

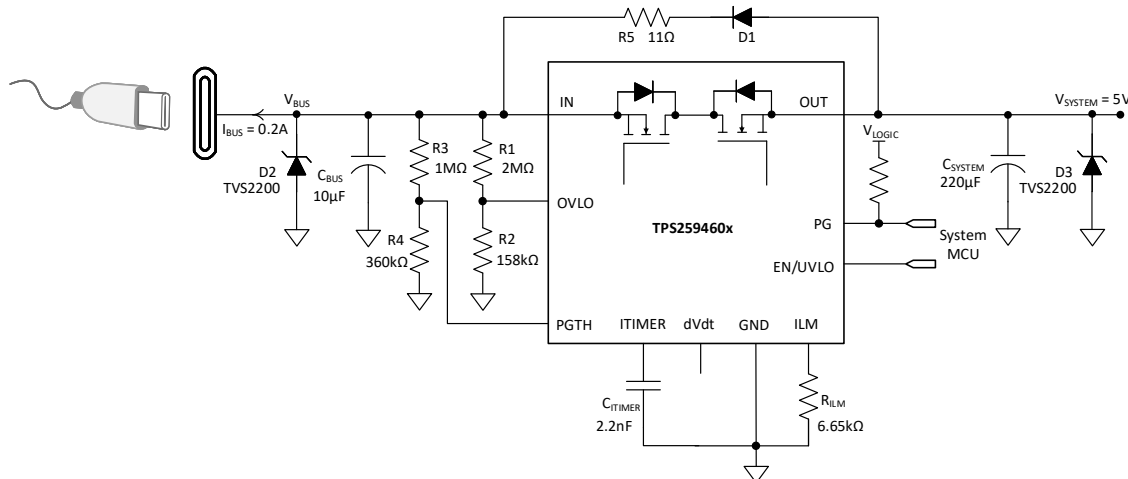


Figure 5-14. Schematic to Evaluate USB On-The-Go (OTG) Port Protection Performance of TPS25946x eFuse

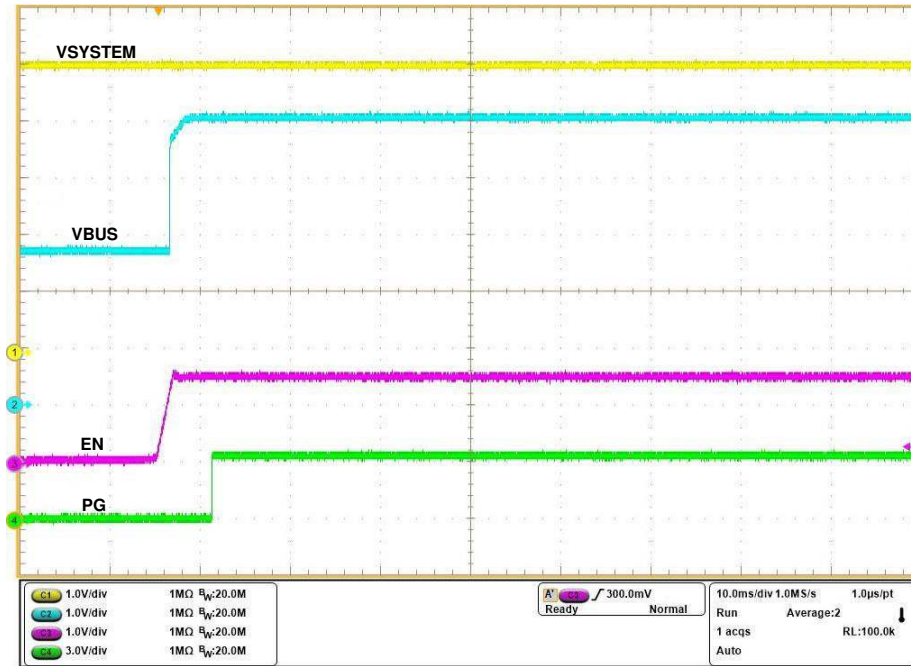


Figure 5-15. Power-Up of TPS25946 eFuse During USB On-The-Go (OTG) Mode (VSYSTEM = 5 V, IBUS = 0.2 A, CdVdt = OPEN)

6 EVAL Board Assembly Drawings and Layout Guidelines

6.1 PCB Drawings

Figure 6-1 shows component placement of the EVAL Board. Figure 6-2 shows PCB layout images.

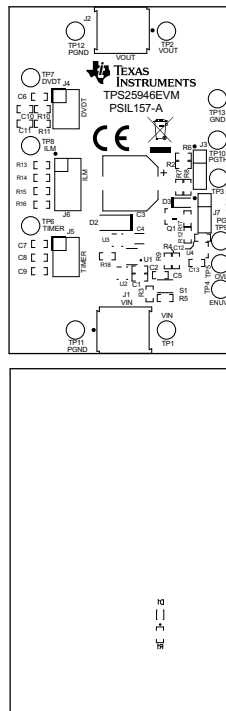


Figure 6-1. TPS25946EVM Board (a) Top Assembly (b) Bottom Assembly

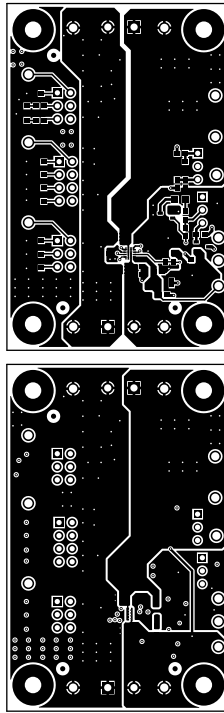


Figure 6-2. TPS25946EVM Board (a) Top Layer (b) Bottom Layer

7 Bill Of Materials (BOM)

Table 7-1 lists the EVM BOM.

Table 7-1. TPS25946EVM BOM

Comment	Description	Designator	Footprint	LibRef	Quantity
C1608X7R1V105K080AC	CAP, CERM, 1 uF, 35 V, +/- 10%, X7R, 0603	C1	0603	CMP-0007052-4	1
C1608X7R1H104K080AA	CAP, CERM, 0.1 uF, 50 V, +/- 10%, X7R, 0603	C2	0603	CMP-0007044-1	1
EEE-FC1V221P	CAP, AL, 220 uF, 35 V, +/- 20%, 0.15 ohm, SMD	C3	SM_RADIAL_G	CMP-0010667-1	1
CGA5L1X7R1H106K160AC	CAP, CERM, 10 uF, 50 V, +/- 10%, X7R, AEC-Q200 Grade 1, 1206	C4	1206_190	CMP-0085950-1	1
885012006057	CAP, CERM, 100 pF, 50 V, +/- 5%, C0G/NP0, 0603	C5	0603	CMP-0006822-4	1
C0603X332K5RACTU	CAP, CERM, 3300 pF, 50 V, +/- 10%, X7R, 0603	C6	0603	CMP-0006985-4	1
C0603C221K5RACTU	CAP, CERM, 220 pF, 50 V, +/- 10%, X7R, 0603	C7	0603	CMP-0006895-2	1
C0603C222K5RACTU	CAP, CERM, 2200 pF, 50 V, +/- 10%, X7R, 0603	C8	0603	CMP-0006898-4	1
C0603X223K5RACTU	CAP, CERM, 0.022 uF, 50 V, +/- 10%, X7R, 0603	C9, C11	0603	CMP-0006984-4	2
GRM1885C1H103JA01D	CAP, CERM, 0.01 uF, 50 V, +/- 5%, C0G/NP0, 0603	C10	0603	CMP-0007174-4	1
06035C104KAT2A	CAP, CERM, 0.1 uF, 50 V, +/- 10%, X7R, 0603	C12, C13	0603	CMP-0006802-4	2
B0530WS-7-F	DIODE SCHOTTKY 30V 500MA SOD323	D1	FP-B0530WS-7-F_SOD323-MFG	CMP-0091894-1	1
B330A-13-F	Diode, Schottky, 30 V, 3 A, SMA	D2	SMA	CMP-0028350-2	1
LTST-C170KGKT	LED, Green, SMD	D3	LTST-C170KGKT_Green	CMP-0002888-1	1
Fiducial	Fiducial mark. There is nothing to buy or mount.	FID1, FID2, FID3, FID4, FID5, FID6	Fiducial10-20	CMP-0077181-1	6

Table 7-1. TPS25946EVM BOM (continued)

Comment	Description	Designator	Footprint	LibRef	Quantity
NY PMS 440 0025 PH	Machine Screw, Round, #4-40 x 1/4, Nylon, Philips panhead	H1, H2, H3, H4	NY PMS 440 0025 PH	CMP-0003617-1	4
1902C	Standoff, Hex, 0.5"L #4-40 Nylon	H5, H6, H7, H8	Keystone_1902C	CMP-0003610-1	4
282841-2	Terminal Block, 2x1, 5.08mm, TH	J1, J2	TEC_282841-2	CMP-0054973-1	2
Header_3x1_Launchpad	Header, 100mil, 3x1, Tin, TH	J3, J7	CONN_PEC03SAAN	CMP-0002338-1	2
PEC03DAAN	Header, 100mil, 3x2, Tin, TH	J4, J5	SULLINS_PEC03DAAN	CMP-0054552-1	2
PEC04DAAN	Header, 100mil, 4x2, Tin, TH	J6	CONN_PEC04DAAN	CMP-0054542-1	1
2N7002	MOSFET, N-CH, 60 V, 115 A, SOT-23	Q1	SOT-23	CMP-0000768-1	1
RC0603FR-0711RL	RES, 11.0, 1%, 0.1 W, 0603	R1	0603	CMP-0022767-4	1
RC0603FR-071ML	RES, 1.00 M, 1%, 0.1 W, 0603	R2, R7	0603	CMP-0022899-4	2
RC0603FR-072ML	RES, 2.00 M, 1%, 0.1 W, 0603	R3, R4	0603	CMP-0023004-4	2
RC0603FR-07249KL	RES, 249 k, 1%, 0.1 W, 0603	R5	0603	CMP-0022941-4	1
CRCW0603124KFKEA	RES, 124 k, 1%, 0.1 W, AEC-Q200 Grade 0, 0603	R6, R8	0603	CMP-0022026-4	2
RC0603FR-07158KL	RES, 158 k, 1%, 0.1 W, 0603	R9	0603	CMP-0022812-4	1
RC0603FR-07100RL	RES, 100, 1%, 0.1 W, 0603	R10, R11	0603	CMP-0022736-4	2
RG1608P-103-B-T5	RES, 10.0 k, 0.1%, 0.1 W, 0603	R12	0603	CMP-0023404-3	1
RC0603FR-076K65L	RES, 6.65 k, 1%, 0.1 W, 0603	R13	0603	CMP-0023251-5	1
RC0603FR-071K65L	RES, 1.65 k, 1%, 0.1 W, 0603	R14	0603	CMP-0022885-5	1
RC0603FR-07750RL	RES, 750, 1%, 0.1 W, 0603	R15	0603	CMP-0023266-5	1
RC0603FR-07549RL	RES, 549, 1%, 0.1 W, 0603	R16	0603	CMP-0023179-5	1
RC0603FR-071KL	RES, 1.00 k, 1%, 0.1 W, 0603	R17	0603	CMP-0022895-5	1
ERJ-3GEY0R00V	RES, 0, 5%, 0.1 W, 0603	R18	0603	CMP-0025874-2	1
B3U-1000P	SWITCH TACTILE SPST-NO 0.05A 12V	S1	SW_B3U-1000P	CMP-0002150-2	1
SPC02SYAN	Shunt, 100mil, Flash Gold, Black	SH-J3, SH-J4, SH-J5, SH-J6, SH-J7	SPC02SYAN	CMP-0003642-1	5

Table 7-1. TPS25946EVM BOM (continued)

Comment	Description	Designator	Footprint	LibRef	Quantity
VIN	Test Point, Multipurpose, Red, TH	TP1	Keystone5010	CMP-0055147-1	1
VOUT	Test Point, Multipurpose, Red, TH	TP2	Keystone5010	CMP-0055147-1	1
VCC_EXT	Test Point, Multipurpose, Orange, TH	TP3	Keystone5013	CMP-0055150-1	1
EN/UVLO	Test Point, Multipurpose, White, TH	TP4	Keystone5012	CMP-0055149-1	1
OVLO	Test Point, Multipurpose, White, TH	TP5	Keystone5012	CMP-0055149-1	1
ITIMER	Test Point, Multipurpose, White, TH	TP6	Keystone5012	CMP-0055149-1	1
dVdt	Test Point, Multipurpose, White, TH	TP7	Keystone5012	CMP-0055149-1	1
ILM	Test Point, Multipurpose, White, TH	TP8	Keystone5012	CMP-0055149-1	1
PG	Test Point, Multipurpose, White, TH	TP9	Keystone5012	CMP-0055149-1	1
PGTH	Test Point, Multipurpose, White, TH	TP10	Keystone5012	CMP-0055149-1	1
PGND	Test Point, Multipurpose, Black, TH	TP11, TP12	Keystone5011	CMP-0055148-1	2
GND	Test Point, Multipurpose, Black, TH	TP13	Keystone5011	CMP-0055148-1	1
TPS259460ARPWR	2.7- 23V, 5.5 A, 28 mΩ eFuse with bi-directional current support, VQFN-HR10	U1	RPW0010A-MFG	CMP-0091678-1	1
TVS2200DRVR	22-V Precision Surge Protection Clamp, DRV0006A (WSON-6)	U2, U3	DRV0006A	CMP-0077834-1	2
LM3480IM3-3.3/NOPB	100 mA, Quasi Low-Dropout Linear Voltage Regulator, 3-pin SOT-23, Pb-Free	U4	DBZ0003A_N	CMP-0071020-1	1

8 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision * (May 2021) to Revision A (August 2021)	Page
• Incorporated the way-out to evaluate TPS259461x variants from TPS25946 eFuse family.....	4

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